

Special Issue

Advanced Biometrics with Deep Learning

Message from the Guest Editors

Biometrics such as fingerprint, iris, face, hand print, hand vein, speech and gait recognition etc. as a means of identity management has become commonplace nowadays for various applications. Biometric systems follow a typical pipeline that is composed of separate preprocessing, feature extraction and classification. Deep learning as a data-driven representation learning approach has been shown to be a promising alternative to conventional data-agnostic and handcrafted preprocessing and feature extraction for biometric systems. Furthermore, deep learning offers an end-to-end learning paradigm to unify preprocessing, feature extraction and recognition based solely on biometric data. The objective of this Special Issue is to invite high-quality, state-of-the-art research papers that deal with challenging issues in advanced deep learning-based biometric systems. We solicit the original papers of unpublished and completed research that are not currently under review by any other conference/magazine/journal.

Guest Editors

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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